


<b>Search Notes</b>  	<b>Application/Control No.</b>  10695259	<b>Applicant(s)/Patent Under Reexamination</b>  TAN, WAI-TIAN
	<b>Examiner</b>  Nguyen-Ba, Hoang-Vu A	<b>Art Unit</b>  2421

SEARCHED			
Class	Subclass	Date	Examiner
725	149	8/23/07	HAN

SEARCH NOTES		
Search Notes	Date	Examiner
East Text Search – USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	8/23/07	HAN
East Text Search – USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	10/22/08	HAN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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